

STP12NM50N-VB Datasheet

N-Channel 650V (D-S) Super Junction Power MOSFET

PRODUCT SUMMARY						
V _{DS} (V) at T _J max.	650					
R _{DS(on)} at 25 °C (Ω)	$V_{GS} = 10 V$	0.23				
Q _g Typ. (nC)	24					
Q _{gs} (nC)	6					
Q _{gd} (nC)	11					
Configuration	Single					

FEATURES

- Low figure-of-merit (FOM) Ron x Qa
- Low input capacitance (C_{iss})
- · Reduced switching and conduction losses
- Ultra low gate charge (Q_q)
- Avalanche energy rated (UIS)

APPLICATIONS

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
 - High-intensity discharge (HID)
 - Fluorescent ballast lighting
- Industrial
 - Welding
 - Induction heating
 - Motor drives
 - Battery chargers
 - Renewable energy
 - Solar (PV inverters)

ABSOLUTE MAXIMUM RATINGS (T_C = 25 °C, unless otherwise noted) SYMBOL PARAMETER LIMIT UNIT **Drain-Source Voltage** 650 V_{DS} V Gate-Source Voltage ± 30 V_{GS} $T_C = 25 \ ^\circ C$ 15 Continuous Drain Current (T_J = 150 °C) V_{GS} at 10 V I_D T_C = 100 °C 10 А Pulsed Drain Current a 45 I_{DM} Linear Derating Factor 1.4 W/°C Single Pulse Avalanche Energy ^b 286 E_{AS} mJ P_D Maximum Power Dissipation 180 W °C Operating Junction and Storage Temperature Range -55 to +150 T_J, T_{stg} Drain-Source Voltage Slope T_{.1} = 125 °C 37 dV/dt V/ns Reverse Diode dV/dt d 23 Soldering Recommendations (Peak Temperature) ^c 300 °C for 10 s

Notes

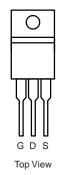
a. Repetitive rating; pulse width limited by maximum junction temperature.

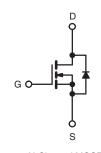
b. V_{DD} = 50 V, starting T_J = 25 °C, L = 28.2 mH, R_g = 25 Ω , I_{AS} = 4.5 A.

c. 1.6 mm from case.

d. $I_{SD} \leq I_D, \, dI/dt = 100$ A/µs, starting $T_J = 25 \ ^\circ C.$

TO-220AB





N-Channel MOSFET





THERMAL RESISTANCE RATI	NGS							
PARAMETER	SYMBOL	TYP.		MAX.		UNIT		
Maximum Junction-to-Ambient	R _{thJA}	- 62						
Maximum Junction-to-Case (Drain)	R _{thJC}	- 0.7				°C/W		
SPECIFICATIONS (T _J = 25 °C, u	nless otherwi	se noted)						
PARAMETER	SYMBOL	TES	T CONDIT	IONS	MIN.	TYP.	MAX.	UNIT
Static					•			
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} =	= 0 V, I _D =	250 µA	650	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C,	I _D = 1 mA	-	0.75	-	V/°C
Gate-Source Threshold Voltage (N)	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D =	250 µA	2	-	4	V
		$V_{GS} = \pm 20 \text{ V}$		V	-	-	± 100	nA
Gate-Source Leakage	I _{GSS}	$V_{GS} = \pm 30 \text{ V}$		-	-	± 1	μA	
		V _{DS} =	= 650 V, V _C	_{as} = 0 V	-	-	1	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 520 V	$D_{S} = 520 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 125 \text{ °C}$		-	-	10	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V		I _D = 8 A	-	0.23	-	Ω
Forward Transconductance	g _{fs}	V _{DS}	= 30 V, I _D	= 8 A	-	5.6	-	S
Dynamic		•						
Input Capacitance	C _{iss}	$\label{eq:VGS} \begin{array}{c} V_{GS}=0 \ V, \\ V_{DS}=100 \ V, \\ f=1 \ MHz \end{array}$		-	1640	-	pF	
Output Capacitance	Coss			-	80	-		
Reverse Transfer Capacitance	C _{rss}			-	4	-		
Effective Output Capacitance, Energy Related ^a	C _{o(er)}	$V_{DS} = 0 V \text{ to } 520 V, V_{GS} = 0 V$		-	63	-		
Effective Output Capacitance, Time Related ^b	C _{o(tr)}			-	213	-		
Total Gate Charge	Qg	V _{GS} = 10 V I _D = 8 A, V _{DS} = 520 V		-	24	48	nC	
Gate-Source Charge	Q _{gs}			-	6	-		
Gate-Drain Charge	Q _{gd}			-	11	-		
Turn-On Delay Time	t _{d(on)}	V_{DD} = 520 V, I_D = 8 A, V_{GS} = 10 V, R_g = 9.1 Ω		-	18	36	ns	
Rise Time	t _r			-	24	48		
Turn-Off Delay Time	t _{d(off)}			-	48	96		
Fall Time	t _f			-	25	50		
Gate Input Resistance	Rg	f = 1 MHz, open drain		-	0.8	-	Ω	
Drain-Source Body Diode Characteristic	s	T			1			
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	15	^	
Pulsed Diode Forward Current	I _{SM}			-	-	38	A	
Diode Forward Voltage	V _{SD}	$T_{\rm J} = 25 \ ^{\circ}{\rm C}, \ I_{\rm S} = 8 \ {\rm A}, \ V_{\rm GS} = 0 \ {\rm V}$		-	-	1.2	V	
Reverse Recovery Time	t _{rr}	$T_{J} = 25 \text{ °C}, I_{F} = I_{S} = 8 \text{ A},$ dl/dt = 100 A/µs, V _R = 400 V		-	325	-	ns	
Reverse Recovery Charge	Q _{rr}			-	4.6	-	μC	
Reverse Recovery Current	I _{RRM}			-	20	_	A	

Notes

a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} . b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} .



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

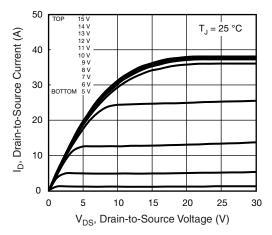


Fig. 1 - Typical Output Characteristics

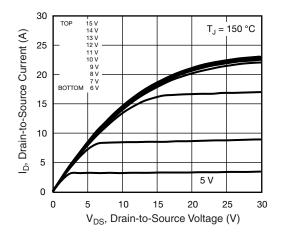


Fig. 2 - Typical Output Characteristics

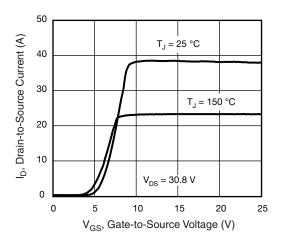


Fig. 3 - Typical Transfer Characteristics

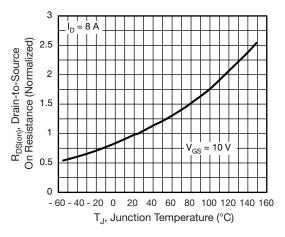


Fig. 4 - Normalized On-Resistance vs. Temperature

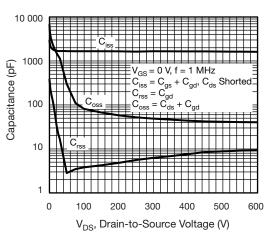


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

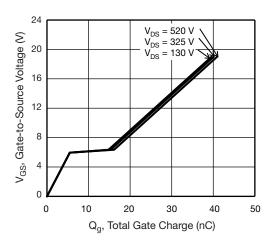


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

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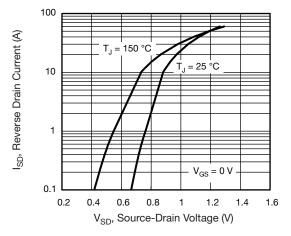


Fig. 7 - Typical Source-Drain Diode Forward Voltage

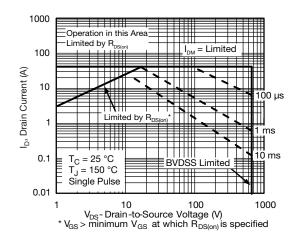


Fig. 8 - Maximum Safe Operating Area

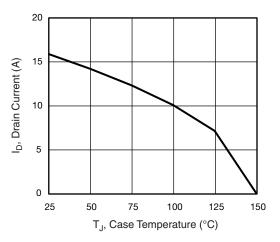


Fig. 9 - Maximum Drain Current vs. Case Temperature

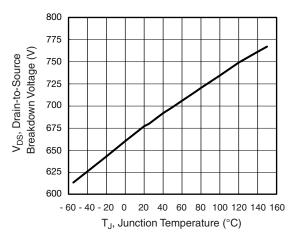


Fig. 10 - Temperature vs. Drain-to-Source Voltage

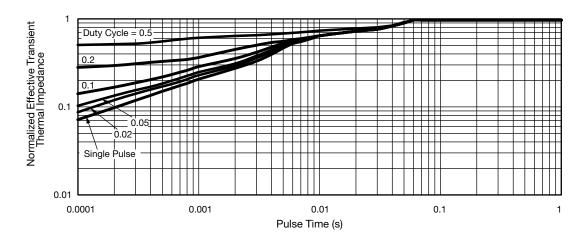


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case

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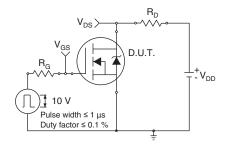


Fig. 12 - Switching Time Test Circuit

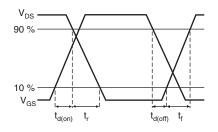


Fig. 13 - Switching Time Waveforms

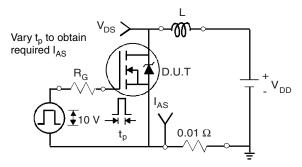


Fig. 14 - Unclamped Inductive Test Circuit

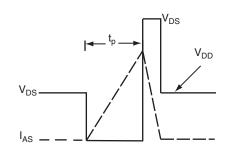


Fig. 15 - Unclamped Inductive Waveforms

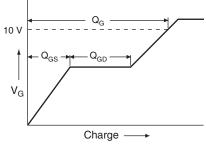


Fig. 16 - Basic Gate Charge Waveform

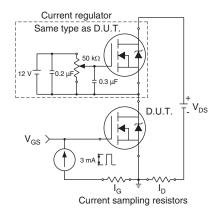
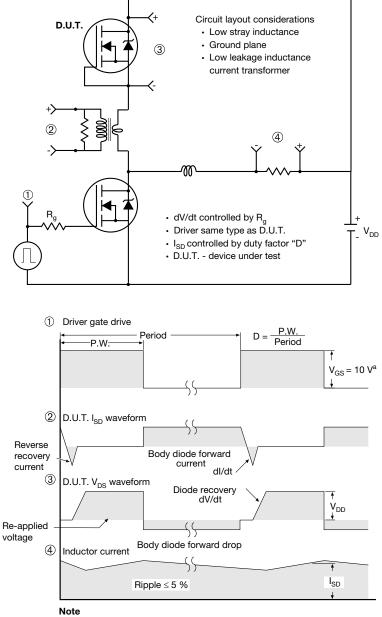


Fig. 17 - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit

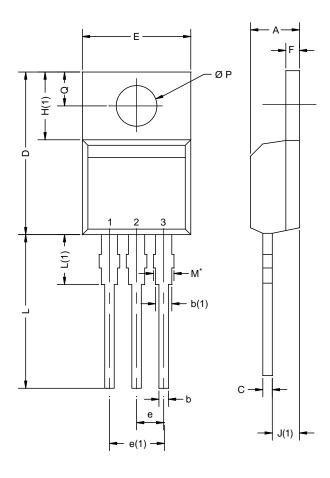


a. $V_{GS} = 5$ V for logic level devices

Fig. 18 - For N-Channel



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	MILLIN	IETERS	INCHES			
DIM.	MIN.	MAX.	MIN.	MAX.		
А	4.25	4.65	0.167	0.183		
b	0.69	1.01	0.027	0.040		
b(1)	1.20	1.73	0.047	0.068		
С	0.36	0.61	0.014	0.024		
D	14.85	15.49	0.585	0.610		
E	10.04	10.51	0.395	0.414		
е	2.41	2.67	0.095	0.105		
e(1)	4.88	5.28	0.192	0.208		
F	1.14	1.40	0.045	0.055		
H(1)	6.09	6.48	0.240	0.255		
J(1)	2.41	2.92	0.095	0.115		
L	13.35	14.02	0.526	0.552		
L(1)	3.32	3.82	0.131	0.150		
Ø P	3.54	3.94	0.139	0.155		
Q	2.60	3.00	0.102	0.118		
ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471						

Notes

 * M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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